

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/042,072	HAUN ET AL.	
Examiner Christopher Bottorff		Art Unit 3618	Page 1 of 1	

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-2,492,410	12-1949	Arps	280/500
B	US-2,537,553	01-1951	Schonauer	280/491.1
C	US-3,622,174	11-1971	Wakeen et al.	280/760
D	US-3,815,701	06-1974	Mayhew, Roger D.	180/69.21
E	US-4,288,490	09-1981	Alfter et al.	428/314.8
F	US-4,681,302	07-1987	Thompson, Marion L.	256/13.1
G	US-6,082,477	07-2000	Murakawa, Masatake	180/69.21
H	US-6,155,580	12-2000	Symons, Ronny	280/33.991
I	US-6,206,122	03-2001	Boothman et al.	180/89.17
J	US-6,290,271	09-2001	Geisler, Richard J.	293/115
K	US-6,318,773	11-2001	Storer, Ron D.	293/115
L	US-6,416,847	07-2002	Lein et al.	428/209
M	US-6,460,916	10-2002	Mizuta, Fumio	296/183

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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